

Analysis and improvement of resilience for long short-term memory neural networks

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APPRAISER : DNN fault resilience analysis employing approximation errors

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Assessment and Enhancement of Hardware Reliability for Deep Neural Networks = Riistvara töökindluse hindamine ja täiustamine süvanärvivõrkude jaoks

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Cost-effective fault tolerance for CNNs using parameter vulnerability based hardening and pruning

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DeepAxe : a framework for exploration of approximation and reliability trade-offs in DNN accelerators

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ECS an endeavor towards providing similar cache reliability behavior in different programs

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Special session : approximation and fault resiliency of DNN accelerators

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Special session: reliability assessment recipes for DNN accelerators

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